Amendments to the Claims:

This listing of claims will replace all prior version, and listings, of claims in the application:

Listing of Claims:

1-8. (Canceled).

9. (New) A circuit configuration for inductive displacement measurement, comprising:

a sensor whose inductance changes as a function of a displacement to be measured; and

an evaluation circuit coupled to the sensor;

wherein:

the sensor is coupled between a first operational amplifier and a series connection of a second operational amplifier and a resistor,

the first operational amplifier is switchable between a first set of two specified voltages and the second operational amplifier is operable to adjust a specified constant voltage at a connecting point between the resistor and the sensor,

an output of the second operational amplifier is connected to an input of a comparator whose other input is switchable between a second set of two specified voltages, and

the output signal of the comparator effects the switchover of the second set of two specified voltages and the first set of two specified voltages of the first operational amplifier, and is a measuring output signal of the circuit configuration at the same time.

10. (New) The circuit configuration of claim 9, further comprising: controllable switches, for switching over the first and second sets of specified voltages of the first operational amplifier and of the comparator, the controllable switches having control inputs which are respectively connected to the output of the comparator.

11. (New) The circuit configuration of claim 9, wherein an input of the second operational amplifier is coupled to the common connecting point of the resistor and the sensor.

12. (New) The circuit configuration of claim 9, wherein an input of the first operational amplifier is connected to its output.

13. (New) The circuit configuration of claim 9, wherein, for measuring the temperature of the sensor, in each case a constant and different voltage is applied to both terminals of the sensor, and after a constant current through the sensor is achieved, a voltage drop at the resistor is evaluated as a measured variable for a temperature-dependent, Ohmic resistance of the sensor.

14. (New) The circuit configuration of claim 13, wherein, for applying the constant and different voltages, there are controllable switches which are controllable by a microcontroller.

15. (New) The circuit configuration of claim 9, wherein a plurality of sensors are each coupled by one terminal in common to the resistor, and respective other terminals of the sensors are coupled to an assigned operational amplifier, whose one input is coupled in each case to an assigned, controllable switch, which is in each case controllable by a microcontroller, and wherein in each case only one sensor is activated and the remaining sensors are deactivated by a same voltage being applied to both of its terminals.

16. (New) The circuit configuration of claim 9, wherein a plurality of sensors is coupled to one terminal in common to the resistor, and respectively other terminals of the sensors are coupled to an assigned operational amplifier, whose one input is coupled respectively to an assigned, controllable switch, which is controllable by a comparator so that a sensor that is to be deactivated has the same voltage applied at both of its terminals when no current flows through it.